

<b>Notice of References Cited</b>	Application/Control No. 10/553,976	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner HENRY S. HU	Art Unit 1796	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2008/0287627 A1	11-2008	Noguchi et al.	526/247
*	B	US-6,110,549	08-2000	Hamada et al.	428/35.2
*	C	US-6,837,918 B2	01-2005	Pozarnsky et al.	95/149
*	D	US-5,541,258	07-1996	Aonuma et al.	525/166
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO-2004/094527 A1	11-2004	WO	Tanaka et al.	-----
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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